



61

Form PTO-1449

## INFORMATION DISCLOSURE CITATION IN AN APPLICATION

#### IN AN APPLICATION

(Use several shovels if necessary)

**Doctor Number (Spain)**

Arbeitsamt Berlin

TSMC-02-1091 10/669,515

Appleton Wen-Tai Wang et al.

Filing Date 09/24/03 Drawn by 2816

## U. S. PATENT DOCUMENTS

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Portion of Page, Etc.)

Kom  
Article "Interconnect and Circuit Modeling Techniques for Full-Chip Power Supply Noise Analysis," by Chen et al., in IEEE Trans. on Components, Packaging, and Manuf. Tech. - Part B, Vol. 21, No. 3, Aug. 1998, pp. 209-215.

EXAMINER	DATE CONSIDERED
WELLS	02/22/05

**EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.



OIP Form PTO-1449

**INFORMATION DISCLOSURE CITATION  
IN AN APPLICATION**

(Use several sheets if necessary)

Doctor Number (Spain)

Agreement Number

TSMC-02-1091

10/669,515

Appleton: Wen-Tai Wang et al.

Filing Date	09/24/03	Groundwork Unit	28/6
-------------	----------	-----------------	------

**U. S. PATENT DOCUMENTS**

## FOREIGN PATENT DOCUMENTS

**OTHER DOCUMENTS** (Including Author, Title, Date, Portion Page, Etc.)

Kaw  
U.S. Patent App. Publication US 2002/0081832 A1 to  
Bernstein et al., Pub. June 27, 2002, "Intralevel  
Decoupling Capacitor, Method of Manufacture and  
Testing Circuit of the Same".

EXAMINER

WELLS

**DATE CONSIDERED**

~~DOEDER~~ 02/22/05

**EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.